•		nent of Commerce	ATTY. DOCKET:	IN RE APPLICATION	
(REV. 8-83) Patent and Transport Supplemental Information DISC STATEMENT		rademark Office	0019696-0154	NO. 09/488,742	
		PEWE	APPLICANT: Otto, et al		
		LUSURER		ERVED 2831	
		111 5 5 5001 F	January 20, 2000	0 3 2001	
(Use s	everal sheets if necessary) \	III SE			
U.S. PATENT DOCUMENTS			Technology Center 2600		
Examiner's Initials	U.S. Patent No.	Applicant	Issue Date	Class Subclass	
1A	5,929,000	Hahakura, et al	July 27, 1999	505 231	
CA	5,912,607	Kalsi, et al	June 15, 1999	335 216	
U	5,828,291	Baumann, et al	October 27, 1998	338 9 32 S	
CM	5,663,528	Tanaka, et al	September 2, 1997	174 125.1	
CM.	5,625,332	Kamo, et al	April 29, 1997	335 216	
A	5,617,280	Hara, et al	April 1, 1997	361 19	
1.10	5,304,534	Ciszek	April 19, 1994	505 434	
a	5,298,679	Wu, et al	March 29, 1994	174 15.4	
a	5,296,456	Shiga, et al	March 22, 1994	505 1	
A	5,017,553	Whitlow, et al	May 21, 1991	505 1	
A	4,994,633	Puhn	February 19, 1991	174 125.1	
A	4,700,257	Bekhaled	October 13, 1987	- 361 19	
(11	4,454,380	Turowski	June 12, 1984	-174 128	
(0)	4,251,328	Tunder	February 17, 1981	204 15	
4	4,079,187	Fillunger, et al	March 14, 1978	174 15 S	
U.S. PATEN	T APPLICATIONS				
Examiner's Initials:	Serial Number:	Applicant:	Filing Date:	Group: Art Unit	
FOREIGN P.	ATENT DOCUMENTS				
Examiner's	Document No.	Country	Date	Translation	
Initials				Yes No	
1	DE 197 46 975 C 1	Denmark	24 October, 1997	Abstract	
OR	EP 0 769 819 A1	Europe	23 April 1997	X	
al	EP 0 786 783 A1	Europe	30 July 1997	X	
M.	JP08171822 (abstract only)	Japan	2 July 1996	X	
A	ЈР6309955	Japan	4 November 1994	Abstract	
all	WO 00/57493	PCT	28 September 2000	X	
a	WO 00/10176	PCT	24 February 2000	X	
(d	WO 94/03955	PCT	17 February 1994	X	
IM	WO 98/14961	PCT	9 April 1998	X	



AUG 0 3 2001.

Technology Center 2600

FORM PTO-14 (REV. 8-83)	U.S. Department of Commerce Patent and Trademark Office	ATTY. DOCKET: 0019696-0154	IN RE APPLICATION NO. 09/488,742		
(IEEV. 0 00)		APPLICANT: Otto, et al			
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT		FILING DATE: January 20, 2000	GROUP: 2831		
(Use sev	veral sheets if necessary)				
OTHER DOC	UMENTS				
Examiner's Initials	Citation (Including Author, Title, Date, Pertinent Pages, Etc.)				
al	Lay, et al., "Over Critical-Current Behavior of Bi-2223 Tapes" IEEE Transactions on Applied Superconductivity., 9 (2):1324-1327, June, 1999				
Cll	Hikichi, et al., "Development of Ag-Mg-α Alloy Sheathed Bi2223 Multifilament Tapes" (Proceedings of the 11th International Symposium of Superconductivity) 915-918, Fukuoka, Japan, November, 1998				
•					

	· · · · · · · · · · · · · · · · · · ·		****		
EXAMINER		DATE CONSIDERED	2/20/8		
	nitial if citation considered, whether or not citation is in	L	9. Draw line through		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

3222966_1.DOC

IDS of 7/25/01 (Paper #6) includes prior art
ited in IDS of 7/3/00 (Paper #3).

Only IDS (Paper #6) will be provided with

2012 this office action